Notice of References Cited	Application/Control No. 10/583,914	Applicant(s)/Patent Under Reexamination BIJKER ET AL.		
	Examiner	Art Unit	Page 1 of 1	
	JAE LEE	2895		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0193857 A1	10-2003	Ichihara et al.	369/47.5
*	В	US-2004/0150326 A1	08-2004	Shibata, Takeshi	313/503
	U	US-			
	ם	US-			
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	٦	US-			
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	C		
	V		
	w		
	х		

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.